Electronic Supplementary Material (ESI) for Journal of Materials Chemistry A.

Supporting information

Figure S1: XRD patterns of carbon-free pure (a) and simple-carbon coated (b) reference samples.

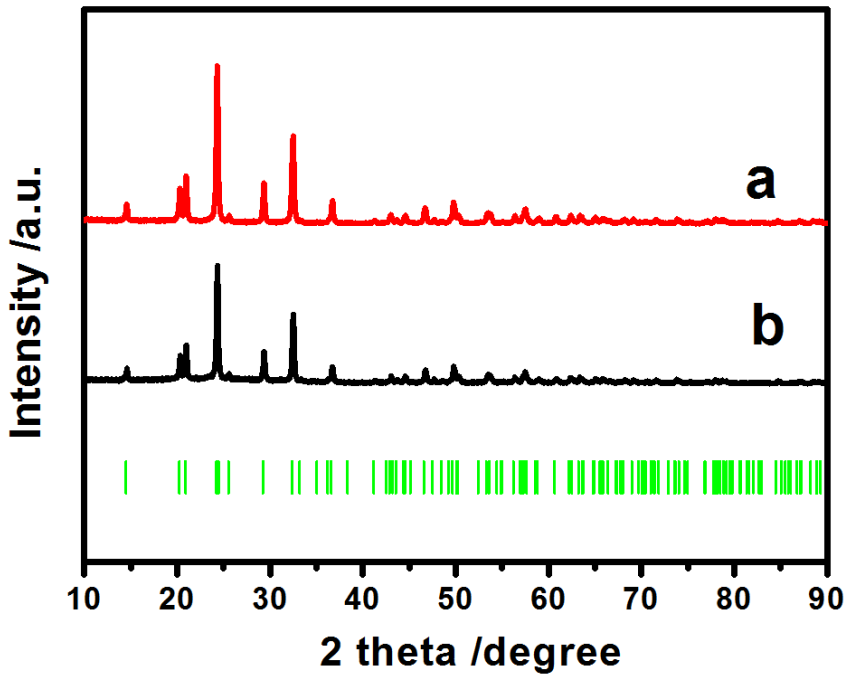

Figure S2: Morphology of simple-carbon coated (NTP/C-S: a,b) and carbon-free pure (NTP/P: c,d) reference samples.

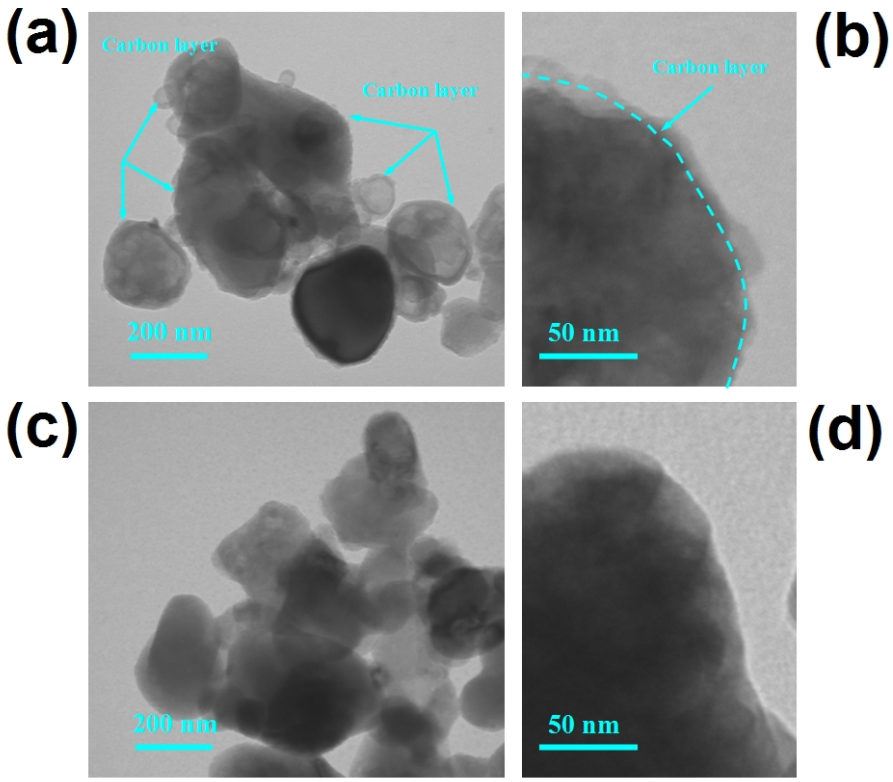

Figure S3: EDX spectroscopy of residual carbon network after HF treatment.

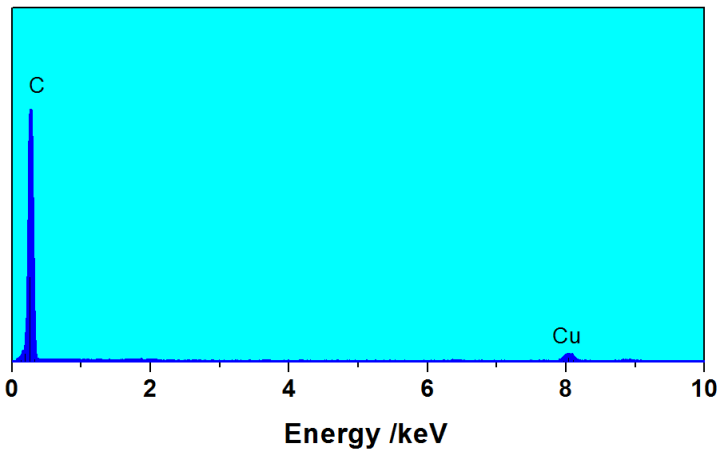

Table S1: Atomic parameters of wafer-like $NaTi_2(PO_4)_3$/C composite refined from the XRD data. NASICON-type structure in space group $R\bar{3}c$. R_{wp}=7.59%, R_P=5.82%.

Atom	**Wyck. site**	***x***	***y***	***z***
Na	6b	0	0	0
Ti	12c	0	0	0.1460
P	18e	0.7145	0	0.25
O1	36f	0.1713	0.1973	0.3014
O2	36f	0.4786	0.2988	0.2475

Table S2: Physical characteristics (BET area, pore volume and carbon content) of the pure (NTP-P), simple carbon coated (NTP/C-S) and wafer-like (NTP/C-W) materials.

Materials	BET area /m^2g^{-1}	Pore volume/m^3g^{-1}	Carbon content/%
NTP/C-W	69.7	0.282	5.12
NTP/C-S	26.1	0.123	4.89
NTP/P	5.8	0.02	0.03